

# ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention	SEMICONDUCTOR DEVICE
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Application Number :

Confirmation Number:

First Named Applicant: Kaoru INOUE

Attorney Docket Number: 28569.7636

Art Unit: 2814

Examiner: Long Pham

Search string: ( 6639255 or 6483135 or 6274889 or 6184547 or 5374835 or 6316793 or 6064082 or 5399886 or 20020066908 ).pn

## US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

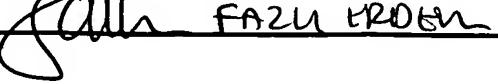
init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
Fe	1	6639255	2003-10-28	Inoue, et al.			
Pg	2	6483135	2002-11-19	Mizuta, et al.			
Pg	3	6274889	2001-08-14	Ota, et al.			
Pg	4	6184547	2001-02-06	Onda			
Pg	5	5374835	1994-12-20	Shimada, et al.			
Pg	6	6316793	2001-11-13	Sheppard, et al.			
Pg	7	6064082	2000-05-16	Kawai, et al.			
Pg	8	5399886	1995-03-21	Hasegawa			

## US Published Applications

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init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
Pg	1	20020066908	2002-06-06	Smith			

## Signature

Examiner Name	Date
 Fazli Trottin	03/10/05

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<b>INFORMATION DISCLOSURE CITATION</b> <small>(Use several sheets if necessary)</small>			ATTY DOCKET NO. 28569.7636		SERIAL NO. 10/711,134	
			Karou INOUE, et al.			
			FILING August 26, 2004	GROUP TBA		
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS
<b>FOREIGN PATENT DOCUMENTS</b>						
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS
TRANSLATION						
YES      NO						
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>						
R8		-	Asbeck, et al., "Piezoelectric charge densities in AlGaN/GaN HFETs," electronic Letters, 3rd July 1997, Vol. 33, No. 14, pp. 1230-1231			
R8		-	Yu, et al., "Piezoelectric enhancement of Schottky barrier heights in GaN/AlGaN HFET structures," Device Research Conference Digest, 1998, 56th Annual, pp. 116-117			
EXAMINER <i>S. Albin</i>			DATE CONSIDERED 03/10/05			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>						

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